



Certificate of Analysis

ULTRAGrade™ Solution
Tantalum ICP / ICP-MS Standard
1000 µg/mL

Catalog Number: ICP-073
Lot Number: CL-2815
Lot Issue Date: 07/21/2014
Expiration Date: 08/31/2021

Starting Material: tantalum metal
Starting Material Purity: 99.99%
Starting Material Lot #: BH01964
Matrix: 0.2% hydrofluoric acid, with trace nitric acid in low TOC water (< 50 ppb)
Atomic Weight Ta: 180.95

Certified Value: 1000 ± 2 µg/mL

This Certified Reference Material (CRM) was manufactured and verified in accordance with ULTRA's ISO 9001 registered quality system. The analyte concentration(s) were prepared and verified by an ISO Guide 34 / ISO 17025 accredited laboratory, and compared to calibration standards independently prepared using NIST SRM(s). The certified value and uncertainty value at the 95% confidence level for each analyte is determined gravimetrically.

Classical Wet Assay Method: Theoretical, based on gravimetric measurements

Confirmation by Inductively Coupled Plasma Spectroscopy (ICP / ICP/MS) vs. NIST SRM 3155

ULTRA uses purified acids, 18 megohm double deionized water, calibrated Class A glassware & meticulously cleaned bottles in the manufacturing of ULTRAGrade standards. Balances used in the manufacturing of this standard are calibrated with weights traceable to NIST in compliance with ANSI/NCSL Z-540-1 and ISO 9001.

Trace Metallic Impurities in Solution Standard in µg/mL:

* Al <0.100 D	* Ga <0.005 ND	n Nb <0.320 D	n S
* Sb <0.005 ND	n Ge	n Os	s Ta
* As <0.005 ND	n Au	* Pd <0.005 ND	n Te
* Ba <0.005 ND	n Hf	* P <0.005 ND	n Tb
* Be <0.005 ND	n Ho	* Pt <0.005 ND	* Tl <0.005 ND
* Bi <0.005 ND	* In <0.005 ND	* K <0.015 D	n Th
* B <0.005 ND	n Ir	n Pr	n Tm
* Cd <0.005 ND	* Fe <0.030 D	n Re	* Sn <0.005 ND
* Ca <0.035 D	* La <0.005 ND	n Rh	* Ti <0.020 D
n Ce	* Pb <0.005 ND	n Rb	n W <0.045 D
n Cs	* Li <0.005 ND	n Ru	n U
* Cr <0.150 D	n Lu	n Sm	* V <0.005 ND
* Co <0.005 ND	* Mg <0.005 ND	n Sc	n Yb
* Cu <0.005 ND	* Mn <0.005 ND	* Se <0.005 ND	n Y
n Dy	* Hg <0.005 ND	* Si <0.005 ND	* Zn <0.005 ND
* Er <0.005 ND	* Mo <0.005 ND	* Ag <0.005 ND	n Zr
* Eu <0.005 ND	n Nd	* Na <0.005 ND	
* Gd <0.005 ND	* Ni <0.120 D	* Sr <0.010 D	

* - element checked for I - spectral interference n - not checked for
ND - not detected D - detected s - solution standard element

Density of Solution (measured at 19.99°C ± 0.05°C): 1.0058 g/mL



ISO 17025:2005 ISO 9001:2000
Accredited Registered
A2LA TUV USA, Inc.
Cert. No. 0851.01 Cert. No. 06-1004

William J. Leary
Quality Assurance Manager